

Search Notes

Application/Control No.

10/699,659

Examiner

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Applicant(s)/Patent under
Reexamination

HSIEH CHEN, YI MEI

Art Unit

3762

SEARCHED

Class	Subclass	Date	Examiner
600	509, 536	5/17/2006	LF

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR